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[Abstract] [PDF Full-Text (193 KB)] IEEE JNL

4 Parameter recharacterization: a method of thermal uprating

Das, D.; Pendse, N.; Wilkinson, C.; Pecht, M.G.; Components and Packaging Technologies, IEEE Transactions on [see also Components, Packaging and Manufacturing Technology, Part A: Packaging Technologies, IEEE Transactions on], Volume: 24, Issue: 4, Dec. 2001 Pages:729 - 737

[Abstract] [PDF Full-Text (139 KB)]

5 Effect fl cal stir and spatial averaging on measurement and testing in m de-tuned and m de-stirred reverberati n chambers

Arnaut, L.R.;

Electromagnetic Compatibility, IEEE Transactions on , Volume: 43 , Issue: 3 , Aug. 2001

Pages: 305 - 325

[Abstract] [PDF Full-Text (724 KB)] IEEE JNI

6 Reliability of conformance tests

Hagwood, C.; Rosenthal, L.;

Reliability, IEEE Transactions on , Volume: 50 , Issue: 2 , June 2001

Pages: 204 - 208

[Abstract] [PDF Full-Text (95 KB)] IEEE JNL

7 A framework for assessing the use of third-party software quality assurance standards to meet FDA medical device software process control guideline's

Bovee, M.W.; Paul, D.L.; Nelson, K.M.;

Engineering Management, IEEE Transactions on , Volume: 48 , Issue: 4 , Nov.

2001

Pages: 465 - 478

[Abstract] [PDF Full-Text (387 KB)] IEEE JNL

8 An algorithm for computations of the power deposition in human tissue

Caputa, K.; Okoniewski, M.; Stuchly, M.A.;

Antennas and Propagation Magazine, IEEE , Volume: 41 , Issue: 4 , Aug. 1999

Pages: 102 - 107

[Abstract] [PDF Full-Text (476 KB)] IEEE JNL

9 VRML testing: making VRML worlds look the same everywhere

Brady, M.; Dima, A.; Gebase, L.; Kass, M.; Montanez-Rivera, C.; Rosenthal, L.; Computer Graphics and Applications, IEEE, Volume: 19, Issue: 2, March-April 1999

Pages: 59 - 67

[Abstract] [PDF Full-Text (376 KB)] IEEE JNL

10 Scientific foundations to the multilevel method

Neelakantan, B.; Raghavan, S.V.;

Networking, IEEE/ACM Transactions on , Volume: 6 , Issue: 3 , June 1998

Pages: 337 - 346

[Abstract] [PDF Full-Text (244 KB)] IEEE JNL

11 SQL Test Suite goes online

Sullivan, J.;

Computer, Volume: 30, Issue: 6, June 1997

Pages: 103, 105

[Abstract] [PDF Full-Text (388 KB)] IEEE JNL

12 Specificati n and testing f the behavi r f netw rk management

agents using SDL-92

Henniger, O.; Barbeau, M.; Sarikaya, B.;

Networking, IEEE/ACM Transactions on , Volume: 4 , Issue: 6 , Dec. 1996

Pages:951 - 961

[Abstract] [PDF Full-Text (1804 KB)] IEEE JNL

13 Evolution of controls for the available bit rate service

Fendick, K.W.;

Communications Magazine, IEEE, Volume: 34, Issue: 11, Nov. 1996

Pages:35 - 39

[Abstract] [PDF Full-Text (676 KB)] IEEE JNL

14 Conformance testing of protocols specified as communicating finite state machines-a guided random walk based approach

Lee, D.; Sabnani, K.K.; Kristol, D.M.; Paul, S.;

Communications, IEEE Transactions on , Volume: 44 , Issue: 5 , May 1996

Pages:631 - 640

[Abstract] [PDF Full-Text (1060 KB)] IEEE JNL

15 Synchronizable test sequences based on multiple UIO sequences

Wen-Huei Chen; Hasan Urai;

Networking, IEEE/ACM Transactions on , Volume: 3 , Issue: 2 , April 1995

Pages: 152 - 157

[Abstract] [PDF Full-Text (576 KB)] IEEE JNL

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Chandra, A.; Iyengar, V.; Jameson, D.; Jawalekar, R.; Nair, I.; Rosen, B.; Mullen, M.; Yoon, J.; Armoni, R.; Geist, D.; Wolfsthal, Y.;

Very Large Scale Integration (VLSI) Systems, IEEE Transactions on , Volume:

3 , Issue: 2 , June 1995

Pages:188 - 200

[Abstract] [PDF Full-Text (1204 KB)] IEEE JNL

17 A correctness criterion for asynchronous circuit validation and optimization

Gopalakrishnan, G.; Brunvand, E.; Michell, N.; Nowick, S.M.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions

on , Volume: 13 , Issue: 11 , Nov. 1994

Pages:1309 - 1318

[Abstract] [PDF Full-Text (880 KB)] IEEE JNL

18 A revised conformance test method of layer 3 of HBS standard

Hamabe, R.; Murata, M.; Honda, Y.; Yamamoto, T.; Kumagai, A.;

Consumer Electronics, IEEE Transactions on , Volume: 40 , Issue: 3 , Aug 1994

Pages: 598 - 604

[Abstract] [PDF Full-Text (524 KB)] IEEE JNL

19 Test selecti n based n communicating nondeterministic finite-state machines using a generalized Wp-meth d

Gang Luo; von Bochmann, G.; Petrenko, A.;

Software Engineering, IEEE Transactions on , Volume: 20 , Issue: 2 , Feb. 1994

Pages:149 - 162

[Abstract] [PDF Full-Text (1088 KB)] IEEE JNL

20 Pr cess assessment with a pr ject f cus

Baumert, J.H.;

Software, IEEE, Volume: 11, Issue: 2, March 1994

Pages:89 - 91

[Abstract] [PDF Full-Text (284 KB)] IEEE JNL

21 Structural analysis of protocol specifications and generation of maximal fault coverage conformance test sequences

Miller, R.E.; Paul, S.;

Networking, IEEE/ACM Transactions on , Volume: 2 , Issue: 5 , Oct. 1994

Pages:457 - 470

[Abstract] [PDF Full-Text (1300 KB)] IEEE JNL

22 On testing hierarchies for protocols

Sidhu, D.P.; Motteler, H.; Vallurupalli, R.;

Networking, IEEE/ACM Transactions on , Volume: 1 , Issue: 5 , Oct. 1993

Pages: 590 - 599

[Abstract] [PDF Full-Text (1044 KB)] IEEE JNL

23 Standards-are software engineering process standards really necessary?

Zelkowitz, M.V.; Buckley, F.J.;

Computer, Volume: 25, Issue: 11, Nov. 1992

Pages:82 - 84

[Abstract] [PDF Full-Text (436 KB)] IEEE JNL

24 Protocol conformance testing using multiple UIO sequences

Shen, Y.-N.; Lombardi, F.; Dahbura, A.T.;

Communications, IEEE Transactions on , Volume: 40 , Issue: 8 , Aug. 1992

Pages:1282 - 1287

[Abstract] [PDF Full-Text (460 KB)] IEEE JNL

25 Evaluation and improvement of fault coverage of conformance testing by UIO sequences

Lombardi, F.; Shen, Y.-N.;

Communications, IEEE Transactions on , Volume: 40 , Issue: 8 , Aug. 1992

Pages:1288 - 1293

[Abstract] [PDF Full-Text (468 KB)] IEEE JNL

26 Testing communication protocols

Naik, K.; Sarikaya, B.;

Software, IEEE, Volume: 9, Issue: 1, Jan. 1992

Pages: 27 - 37

[Abstract] [PDF Full-Text (1920 KB)] IEEE JNL

27 Test generati n from LOTOS specifications

Tripathy, P.; Sarikaya, B.;

Computers, IEEE Transactions on , Volume: 40 , Issue: 4 , April 1991

Pages: 543 - 552

[Abstract] [PDF Full-Text (764 KB)] IEEE JNL

28 A well-defined Estelle specificati n f r the automatic test generati n

Lee, D.Y.; Lee, J.Y.;

Computers, IEEE Transactions on , Volume: 40 , Issue: 4 , April 1991

Pages: 526 - 542

[Abstract] [PDF Full-Text (1144 KB)] IEEE JNL

29 Test selection based on finite state models

Fujiwara, S.; v. Bochmann, G.; Khendek, F.; Amalou, M.; Ghedamsi, A.;

Software Engineering, IEEE Transactions on , Volume: 17 , Issue: 6 , June 1991

Pages:591 - 603

[Abstract] [PDF Full-Text (1260 KB)] IEEE JNL

30 A test sequence selection method for protocol testing

Ural, H.; Yang, B.;

Communications, IEEE Transactions on , Volume: 39 , Issue: 4 , April 1991

Pages:514 - 523

[Abstract] [PDF Full-Text (836 KB)] IEEE JNL

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